

# Optimization of Ni doping to improve thermoelectric properties of $\beta$ -Fe<sub>1-x</sub>Ni<sub>x</sub>Si<sub>2</sub>

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Iron silicide compound is an abundant and non-toxic material which has 3 different kinds of phases namely cubic  $\epsilon$ -phase, tetragonal  $\alpha$ -phase, and orthorhombic  $\beta$ -phase with space group of  $P2_13$ ,  $P4/mmm$ , and  $Cmce$ , respectively.  $\beta$ -FeSi<sub>2</sub> is a semiconductor having a narrow band gap of about 0.73 eV which is relevant in high temperature thermoelectric (TE) application due to strong oxidation resistance and good thermal stability; however, the bipolar effect, which deteriorates the Seebeck coefficient ( $S$ ) as temperature increases, usually occurs in the pristine  $\beta$ -FeSi<sub>2</sub> due to such a small band gap and low carrier concentration ( $n_H$ ) [1-2]. Komabayashi *et al.*, reported that the TE's parameters of thin film's Fe<sub>0.94</sub>Ni<sub>0.06</sub>Si<sub>2.05</sub> measured at room temperature such as:  $S$ , electrical resistivity ( $\rho$ ), and power factor ( $PF = S^2\rho^{-1}$ ) was -113  $\mu$ V/K, 0.076  $\Omega$ .cm, and 17  $\mu$ W.m<sup>-1</sup>. K<sup>-2</sup>, respectively [3]. In addition, Tani and Kido reported that the  $\rho$  of bulk's  $\beta$ -Fe<sub>1-x</sub>Ni<sub>x</sub>Si<sub>2</sub> increases with the addition of Ni amount owing to the increase in  $n_H$  [4], which is also significant to the reduction of bipolar effect. However, the optimum doping level of Ni to enhance the  $PF$  and the effect of Ni to thermal conductivity ( $\kappa$ ) as well as TE's performance ( $ZT = S^2\rho^{-1}\kappa^{-1}T$ ) of  $\beta$ -FeSi<sub>2</sub> has not yet been investigated. In the current work, we have studied in detail about the effect and the optimization of Ni dopant on the TE's properties of bulk's  $\beta$ -Fe<sub>1-x</sub>Ni<sub>x</sub>Si<sub>2</sub> prepared by arc-melting techniques. The powder XRD data were measured by CuK $\alpha$  diffractometer (SmartLab, Rigaku). The  $S$  and  $\rho$  were measured by ResiTest8300 and homemade apparatus, and the  $\kappa$  was measured by power conversion efficiency measurement system (PEM-2, ULVAC-RIKO). As a result, the addition of Ni significantly reduces the bipolar due to the increase in  $n_H$  and the  $S$  of bulk's Ni-doped samples are remarkably more stable than that of non-doped sample above 400 K. We observed that both  $|S|$  and  $\rho$  remarkably decreases with increasing  $x$ , while  $\kappa$  is not significantly varied with  $x$ . The highest  $PF = 130 \mu$ W.m<sup>-1</sup>. K<sup>-2</sup> is obtained in  $\beta$ -Fe<sub>0.99</sub>Ni<sub>0.01</sub>Si<sub>2</sub> at 760K, which is 7 times larger than the thin film sample reported by Komabayashi *et al.*, at room temperature measurement. Therefore, the highest  $ZT = 0.01$  is also obtained in  $\beta$ -Fe<sub>0.99</sub>Ni<sub>0.01</sub>Si<sub>2</sub> at 760 K with  $n_H = 2.3(9) \times 10^{17}$  cm<sup>-3</sup> due to the stability in  $|S|$ , the significant reduction in  $\rho$ , and no remarkable effect in  $\kappa$ .

## References

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